


LIST OF REFERENCES CITED BY APPLICANT
 (Use several sheets if necessary)

ATTY. DOCKET NO.	APPLICATION NO.
9301-159	10/520,031
APPLICANT	
Marton <i>et al.</i>	
FILING DATE	ART UNIT
June 27, 2003	1637

U.S. PATENT DOCUMENTS

*Examiner Initials		Document Number	Date mm/dd/yy	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

FOREIGN PATENT DOCUMENTS

*Examiner Initials		Foreign Patent Document Country Code, Number, Kind Code (if known)	Date mm/dd/yy	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
/YK/	B05	WO 01/36682	05/25/01	Clontech Lab Inc.		
	B06	EP 0 955 085 A2	11/10/99	Affymetrix Inc.		
	B07	GB 2 355 716 A	05/02/01	Agilent Technologies Inc.		
↓	B08	EP 1 179 368 A2	02/13/02	Agilent Technologies Inc.		
↓	B09	WO 99/42813 A	08/26/99	Wisconsin Alumni Res. Found		

NON PATENT LITERATURE DOCUMENTS

*Examiner Initials		Include name of the author (in CAPITAL LETTERS), (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
/YK/	C29	Supplementary European search report dated May 16, 2007 for European Patent Application No. 03 762 218.0 – 1222.	

NYI-4145958v1

EXAMINER	/Young J. Kim/	DATE CONSIDERED	02/03/2009
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			